Supporting Information

"Walljet Electrochemistry: Quantifying Molecular Transport through Metallopolymeric and Zirconium Phosphonate-Assembled Porphyrin Square Thin Films"

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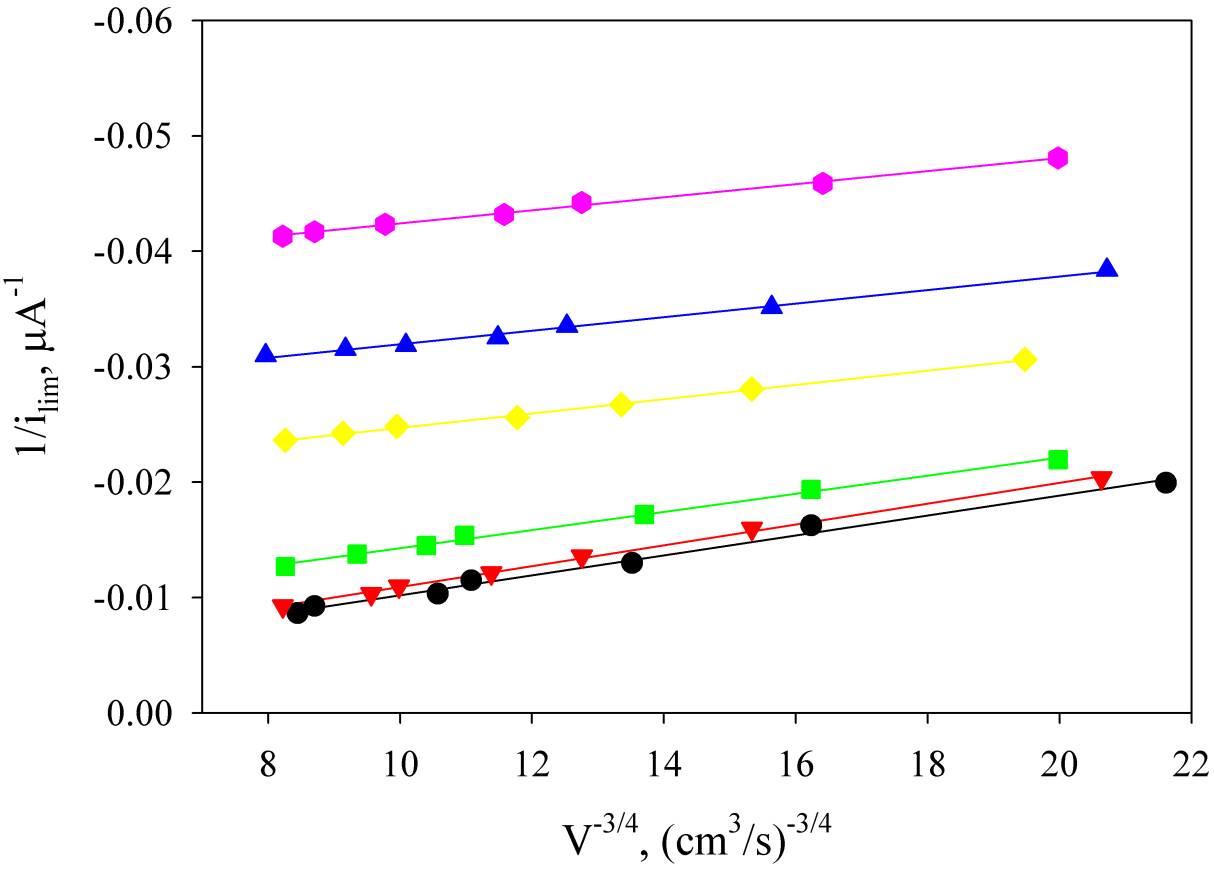

Shown is a representative plot of $1/i_{lim}$ as a function of $V^{-3/4}$ for a sample series with varying thicknesses of ZrP-assembled **4** using FcMeOH as the redox permeant. Shown samples are bare ITO (●), 1 (▼), 3 (■), 5 (◆), 8 (▲), and 10 (⬢) layers. Although the film thicknesses are extremely thin (nanometers to tens of nanometers), the i_{perm} (i.e. y-axis offset) is clearly measurable, even with a small redox probe.